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## ON Semiconductor®

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Nov. 2016

## **FPF2C110BI07AS2**

## F2, Boost and Inverter module with Press-fit

#### **General Description**

Fairchild's Boost and H-Bridge module is designed for a power stage that needs more compact design. And the Press-fit technology provides simple and reliable mounting. This module is optimized for the application such as solar inverter where a high efficiency and robust design are needed.

#### **Electrical Features**

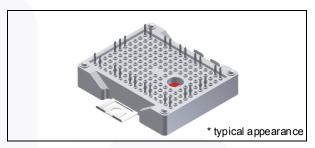
- · Boost Stage
  - Dual Boost Topology
  - SiC Boost Diode
  - Low R<sub>DS(ON)</sub> Boost Switch
  - Low V<sub>F</sub> and High Voltage Bypass Diode
- · Inverter Stage
  - H-bridge Topology
  - High Speed IGBT and Fast Recovery FWD
- · Integrated DC-capacitor for Boost and Inverter
- · Temperature Sensor

#### **Mechanical Features**

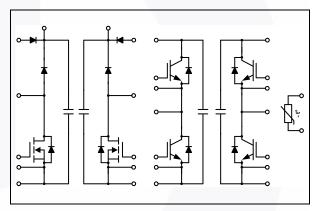
- · Compact size: F2 Package
- Press-fit Contact Technology
- Al<sub>2</sub>O<sub>3</sub> Substrate with Low Thermal Resistance

### **Applications**

Solar Inverter



Package Code: F2



**Internal Circuit Diagram** 

### **Package Marking and Ordering Information**

Device	Device Marking	Package	Packing Type	Quantity / Tray
FPF2C110BI07AS2	FPF2C110BI07AS2	F2	Tray	14

## Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Description	Condition	Rating	Units	
Bypass Dic	ode (DA1, DA2)				
V <sub>RRM</sub>	Peak Repetitive Reverse Voltage		1000	V	
l <sub>F</sub>	Continuous Forward Current	T <sub>C</sub> = 80 °C, T <sub>Jmax</sub> = 175 °C	50	Α	
I <sub>FSM</sub>	Non-repetitive Peak Surge Current	60 Hz Single Half-Sine Wave	350	Α	
I <sup>2</sup> t	Surge Current Integral Value		510	A <sup>2</sup> s	
$P_{D}$	Maximum Power Dissipation	T <sub>Jmax</sub> = 175 °C	300	W	
T <sub>J</sub>	Operating Junction Temperature		- 40 to + 150	°C	
Boost Diod	le (DB1, DB2)				
$V_{RRM}$	Peak Repetitive Reverse Voltage		650	V	
l <sub>F</sub>	Continuous Forward Current	T <sub>C</sub> = 80 °C, T <sub>Jmax</sub> = 175 °C	10	А	
I <sub>FSM</sub>	Non-repetitive Peak Surge Current	60 Hz Single Half-Sine Wave	40	А	
I <sup>2</sup> t	Surge Current Integral Value		6.6	A <sup>2</sup> s	
P <sub>D</sub>	Maximum Power Dissipation	T <sub>Jmax</sub> = 175 °C	90	W	
T <sub>J</sub>	Operating Junction Temperature		- 40 to + 150	°C	
Boost MOS	FET (M1, M2)				
V <sub>DSS</sub>	Drain-Source Voltage		650	V	
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V	
I <sub>D</sub>	Orain Current	T <sub>C</sub> = 25 °C, T <sub>Jmax</sub> = 150 °C	25	Α	
		T <sub>C</sub> = 80 °C, T <sub>Jmax</sub> = 150 °C	19	Α	
I <sub>DM</sub>	Pulsed Drain Current	limited by T <sub>Jmax</sub>	50	Α	
P <sub>D</sub>	Maximum Power Dissipation	T <sub>Jmax</sub> = 150 °C	199	W	
 T <sub>J</sub>	Operating Junction Temperature		- 40 to + 150	°C	
H-bridae IG	BBT (QA, QB, QC, QD)				
V <sub>CES</sub>	Collector-Emitter Voltage		650	V	
V <sub>GES</sub>	Collector-Emitter Voltage  Gate-Emitter Voltage		± 20	V	
I <sub>C</sub>	Collector Current	T <sub>C</sub> = 80 °C, T <sub>Jmax</sub> = 175 °C	40	А	
I <sub>CM</sub>	Pulsed Collector Current	limited by T <sub>Jmax</sub>	80	Α	
$P_{D}$	Maximum Power Dissipation	T <sub>Jmax</sub> = 175 °C	158	W	
T <sub>J</sub>	Operating Junction Temperature		- 40 to + 150	°C	
H-bridge F\	WD (QAD, QBD, QCD, QDD)				
V <sub>RRM</sub>	Peak Repetitive Reverse Voltage		650	V	
I <sub>F</sub>	Diode Forward Current	T <sub>C</sub> = 80 °C, T <sub>Jmax</sub> = 175 °C	30	Α	
I <sub>FM</sub>	Pulsed Maximum Forward Currents	limited by T <sub>Jmax</sub>			
$P_{D}$	Maximum Power Dissipation			W	
T <sub>J</sub>	Operating Junction Temperature		- 40 to + 150	°C	
DC Link Ca	pacitor			I	
V <sub>MAX</sub>	Maximum DC Voltage		1000	V	
T <sub>OP</sub>	Operating Temperature		- 55 to + 125	°C	

## Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Description	Condition	Rating	Units	
Module	•	,		•	
T <sub>STG</sub>	Storage Temperature		- 40 to + 125	°C	
V <sub>ISO</sub>	Isolation Voltage	AC 1 min.	2500		
IsoMaterial	Internal Isolation Material	Al <sub>2</sub> O <sub>3</sub>	-		
T <sub>MOUNT</sub>	Mounting Torque <sub>(1)</sub>		2.4	N•m	
Creepage	Terminal to Heat Sink		11.5	mm	
	Terminal to Terminal		6.3	mm	
Clearance	Terminal to Heat Sink		10.0	mm	
	Terminal to Terminal		5.0	mm	

#### Notes:

1. Recommendable value: 2.0 ~ 2.4 Nm (M4)

## $\textbf{Electrical Characteristics} \ \ \textbf{T}_{\text{C}} = 25\ ^{\circ}\text{C unless otherwise noted.} \ \textbf{Parantheses value is based on the discrete.}$

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
Bypass D	liode (DA1, DA2)					
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> = 50 A	-	1.37	1.7	V
•		I <sub>F</sub> = 50 A, T <sub>C</sub> = 125 °C	_	1.3	_	V
I <sub>R</sub>	Reverse Leakage Current	V <sub>R</sub> = 1000 V	_	-	250	μА
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Diode	_	_	0.49	°C/W
R <sub>0CH</sub>	Thermal Resistance of Case to Heat sink	per Chip, $\lambda_{PCM} = 3.4 \text{ W/mK}$	_	0.56	-	°C/W
		рог отпруждения		0.00		0,11
	ode (DB1, DB2)	10.0	1	1 10	4.50	
$V_{F}$	Diode Forward Voltage	I <sub>F</sub> = 10 A	-	1.42	1.58	V
		I <sub>F</sub> = 10 A, T <sub>C</sub> = 125 °C	-	1.61	-	
I <sub>R</sub>	Reverse Leakage Current	V <sub>R</sub> = 650 V	-	-	250	μΑ
I <sub>rr</sub>	Reverse Recovery Current	$V_R = 300 \text{ V}, I_F = 10 \text{ A},$ di / dt = 1560 A/us,	-	6	-	Α
Q <sub>C</sub>	Total Capacitive Charge	-17  at  = 1500  A/us, -17  C = 25  °C	-	60	-	nC
E <sub>rec</sub>	Reverse Recovery Energy		-	7.5	-	μJ
I <sub>rr</sub>	Reverse Recovery Current	$V_R = 300 \text{ V}, I_F = 10 \text{ A},$	-	6	-	Α
Q <sub>C</sub>	Total Capacitive Charge	di / dt = 1560 A/us,	-	61	-	nC
E <sub>rec</sub>	Reverse Recovery Energy	T <sub>C</sub> = 125 °C	-	7.5	-	μJ
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Chip	-	-	1.63	°C/W
$R_{\theta CH}$	Thermal Resistance of Case to Heat sink	per Chip, λ <sub>PCM</sub> = 3.4 W/mK	-	0.42	-	°C/W
Boost MC	OSFET (M1, M2)			1.	'	
Off Charac						
V <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA	650	-	-	V
I <sub>DSS</sub>	Drain Cut-off Current	$V_{DS} = V_{DSS}, V_{GS} = 0 \text{ V}$	_	-	250	μА
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = V <sub>GSS</sub> , V <sub>DS</sub> = 0 V	_	_	± 1	μА
On Charac		- 63 - 633, - 63				P** 1
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250uA	3.0	3.9	5.0	V
R <sub>DS(ON)</sub>	Static Drain-Source On Resistance	I <sub>D</sub> = 17.5 A, V <sub>GS</sub> = 10 V	-	110	137	mΩ
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	I <sub>SD</sub> = 17.5 A, V <sub>GS</sub> = 0 V	_	1.07	1.37	V
. 20	Brain course Blode I diward voltage	$I_{SD} = 17.5 \text{ A}, V_{GS} = 0 \text{ V}, T_{C} = 125 ^{\circ}\text{C}$	_	0.93	-	V
R <sub>LEAD</sub>	Lead Resistance of Pin to Chip	per Chip	_	3.2	_	mΩ
	Characteristics	por emp		J 0.1		
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CC</sub> = 300 V	_	27	-	ns
t <sub>r</sub>	Rise Time	I <sub>D</sub> = 17.5 A	_	5.0	_	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}$	_	3.0	_	ns
t <sub>f</sub>	Fall Time	$R_G = 4.7 \Omega$	-	5.5	_	ns
E <sub>ON</sub>	Turn-On Switching Loss per Pulse	Inductive Load  T <sub>C</sub> = 25 °C	_	33	_	μJ
E <sub>OFF</sub>	Turn-Off Switching Loss per Pulse		_	20	_	μЈ
	Turn-On Delay Time	V <sub>CC</sub> = 300 V	_	26	-	μο ns
t <sub>d(on)</sub>	Rise Time	I <sub>D</sub> = 17.5 A		5.3		
t <sub>r</sub>		V <sub>GS</sub> = 10 V	-	5.3 87	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 4.7 \Omega$	-		-	ns
t <sub>f</sub>	Fall Time	Inductive Load	-	6.0	-	ns
E <sub>ON</sub>	Turn-On Switching Loss per Pulse	T <sub>C</sub> = 125 °C	-	39	-	μJ
E <sub>OFF</sub>	Turn-Off Switching Loss per Pulse		-	21	-	μJ
Q <sub>g</sub>	Total Gate Charge	$V_{CC} = 300 \text{ V}, I_{SD} = 17.5 \text{ A}, V_{GS} = 10 \text{ V}$	-	84	-	nC
R <sub>θJC</sub>	Thermal Resistance of Junction to Case	per Chip	-	-	0.63	°C/W
$R_{\theta CH}$	Thermal Resistance of Case to Heat sink	per Chip, $\lambda_{PCM}$ = 3.4 W/mK	-	0.49	-	°C/W

## $\textbf{Electrical Characteristics} \ \ \textbf{T}_{\text{C}} = 25\ ^{\circ}\text{C unless otherwise noted.} \ \textbf{Parantheses value is based on the discrete.}$

Symbol	Parameter Conditions		Min.	Тур.	Max.	Units
H-Bridge	IGBT (QA, QB, QC, QD)					
Off Charac	teristics					
BV <sub>CES</sub>	Collector-Emitter Breakdown Voltage	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 1 mA	650	-	-	V
I <sub>CES</sub>	Collector Cut-off Current	$V_{CE} = V_{CES}, V_{GE} = 0 V$	-	-	250	μΑ
I <sub>GES</sub>	Gate-Emitter Leakage Current	$V_{GE} = V_{GES}$ , $V_{CE} = 0$ V	-	-	± 2	μΑ
On Charac	teristics					
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	$V_{GE} = V_{CE}$ , $I_C = 40 \text{ mA}$	3.0	5.2	6.1	V
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V	-	1.6	2.3	٧
		I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V, T <sub>C</sub> = 125 °C	-	1.8	-	V
R <sub>LEAD</sub>	Lead Resistance of Pin to Chip	per Chip	-	3.5	-	mΩ
Switching	Characteristics (QB-QAD / QD-QCD)					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CC</sub> = 300 V	-	26	-	ns
t <sub>r</sub>	Rise Time	I <sub>C</sub> = 40 A - V <sub>GE</sub> = 15 V	-	22	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 15 \Omega$	-	125	-	ns
t <sub>f</sub>	Fall Time	Inductive Load	-	14	-	ns
E <sub>ON</sub>	Turn-On Switching Loss per Pulse	T <sub>C</sub> = 25 °C	-	0.45	-	mJ
E <sub>OFF</sub>	Turn-Off Switching Loss per Pulse		-	0.27	-	mJ
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CC</sub> = 300 V	-	24	-	ns
t <sub>r</sub>	Rise Time	I <sub>C</sub> = 40 A - V <sub>GE</sub> = 15 V	-	25	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 15 \Omega$	-	139	-	ns
t <sub>f</sub>	Fall Time	Inductive Load	-	13	-	ns
E <sub>ON</sub>	Turn-On Switching Loss per Pulse	T <sub>C</sub> = 125 °C	-	0.74	-	mJ
E <sub>OFF</sub>	Turn-Off Switching Loss per Pulse		-	0.35	-	mJ
Qg	Total Gate Charge	V <sub>CC</sub> = 300 V, I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V	-	60	-	nC
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Chip	-	-	0.95	°C/W
$R_{\theta CH}$	Thermal Resistance of Case to Heat sink per Chip, $\lambda_{PCM}$ = 3.4 W/mK		-	0.64	-	°C/W
H-bridge	FWD (QAD, QBD, QCD, QDD)					
V <sub>F</sub>	Diode Forward Voltage	I <sub>E</sub> = 30 A	Т-	2.45	3.2	V
*F	Blodd Forward Vollage	I <sub>F</sub> = 30 A, T <sub>C</sub> = 125 °C	-	2.15	-	V
I <sub>R</sub>	Reverse Leakage Current	V <sub>R</sub> = 650 V		-	250	μА
I <sub>rr</sub>	Reverse Recovery Current	V <sub>R</sub> = 300 V, I <sub>F</sub> = 30 A,	/-	20.1		A
t <sub>rr</sub>	Reverse Recovery Time	di / dt = 1570 A/us,	_	30	_	ns
E <sub>rec</sub>	Reverse Recovery Energy	T <sub>C</sub> = 25 °C	_	27	_	μJ
	Reverse Recovery Current	V <sub>R</sub> = 300 V, I <sub>F</sub> = 30 A,	-	23.1	_	A
t <sub>rr</sub>	Reverse Recovery Time	di / dt = 1135 A/us,	_	52	_	ns
E <sub>rec</sub>	Reverse Recovery Energy	T <sub>C</sub> = 125 °C	_	73	_	μЈ
R <sub>θJC</sub>	Thermal Resistance of Junction to Case	per Chip	-	-	1.38	°C/W
R <sub>θCH</sub>	Thermal Resistance of Case to Heat sink	per Chip, $\lambda_{PCM} = 3.4 \text{ W/mK}$	-	0.45	-	°C/W
		For our Figure 1				
DC link C				1		
C value	Capacitance Value		-	47	-	nF
NTC (The	rmistor)					
R <sub>NTC</sub>	Rated Resistance	T <sub>C</sub> = 25 °C	-	22	-	kΩ
		T <sub>C</sub> = 100 °C	-	1.486	-	kΩ
	Tolerance	T <sub>C</sub> = 25 °C	-5	-	+5	%
$P_D$	Power Dissipation	T <sub>C</sub> = 25 °C	-	-	20	mW
B <sub>Value</sub>	B-Constance	B <sub>25/50</sub> , tol.	_	3950	-	K
		B <sub>25/100</sub>	-	3998	-	K

Fig 1. Forward Voltage Drop

- Bypass Diode

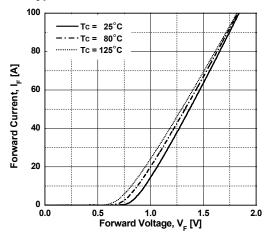


Fig 2. Transient Thermal Impedance
- Bypass Diode

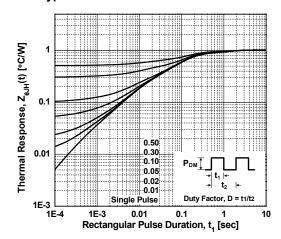


Fig 3. Forward Voltage Drop

- Boost Diode

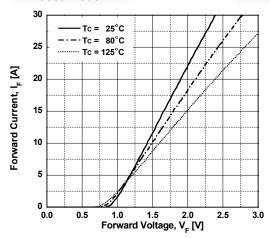


Fig 4. Transient Thermal Impedance

- Boost Diode

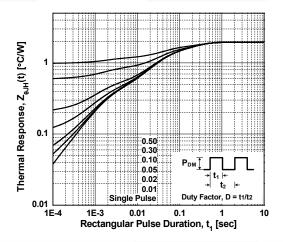


Fig 5. On-Region Characteristics

- Boost MOSFET

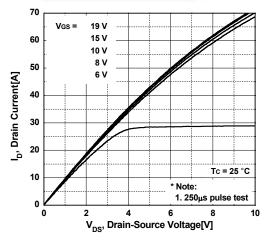


Fig 6. On-Region Characteristics

- Boost MOSFET

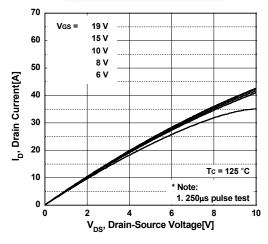


Fig 7. On-Resistance Variation vs. Temperature

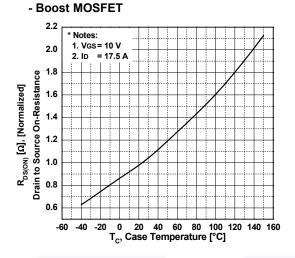


Fig 8. Switching Loss vs. Gate Resistor Values

- Boost MOSFET

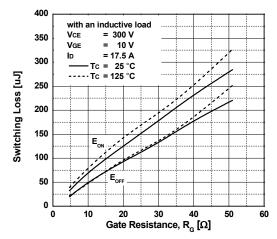


Fig 9. Switching Loss vs. Drain Current - Boost MOSFET

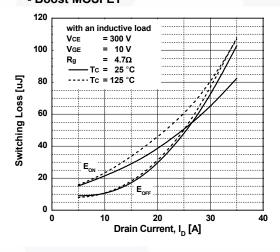


Fig 10. Body Diode Forward Voltage Variation vs. Source Current and Temperature - Boost MOSFET

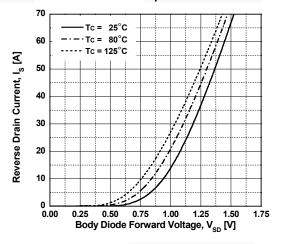
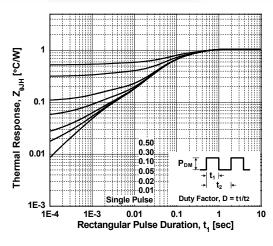


Fig 11. Transient Thermal Impedance - Boost MOSFET



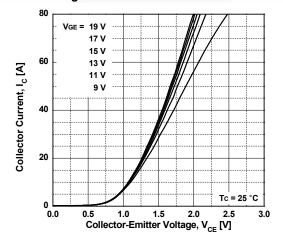


Fig 12. Output Characteristics - H-bridge IGBT

Fig 13. Output Characteristics

- H-bridge IGBT

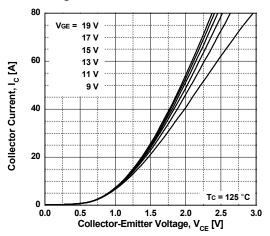


Fig 14. Saturation Voltage Characteristics
- H-bridge IGBT

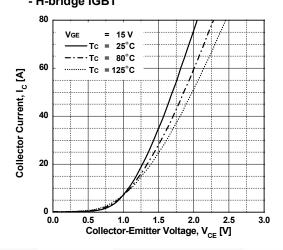


Fig 15. Switching Loss vs. Gate Resistor Values
- H-bridge IGBT

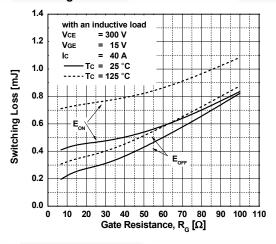


Fig 16. Switching Loss vs. Collector Current
- H-bridge IGBT

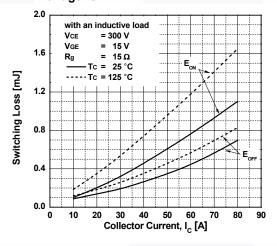


Fig 17. Transient Thermal Impedance
- H-bridge IGBT

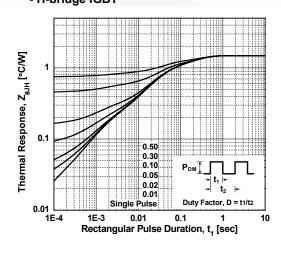


Fig 18. Forward Voltage Drop vs. Forward Current
- H-bridge FWD

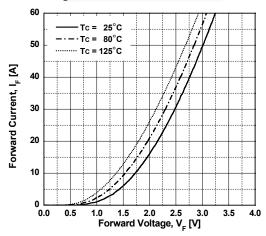


Fig 19. Reverse Recovery Energy vs.

Gate Resistor Values - H-bridge FWD

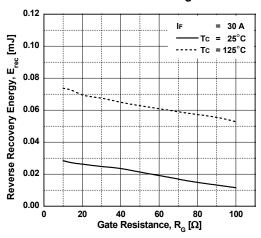


Fig 20. Reverse Recovery Energy vs.

Forward Current - H-bridge FWD

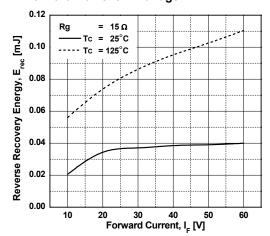
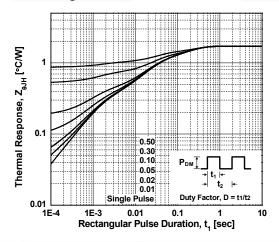
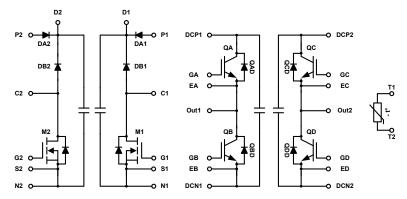


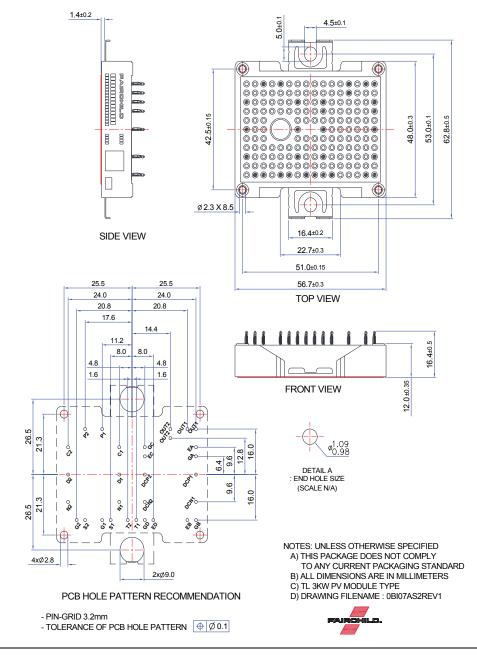
Fig 21. Transient Thermal Impedance
- H-bridge FWD



### **Internal Circuit Diagram**



## Package Outlines [mm]







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Rev. 177

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